

**Proceedings Of The IEEE (May 1993) Special
Issue On VLSI Reliability**

By unknown



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Figure 13. Decoupling Capacitance Hierarchy P.C. Board Power Supply L Proc. VLSI Signal Processing Workshop, IEEE Press, May 1994. [44]N. Seghal, C. Chen and

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Professor Yehea Ismail is the director of the Center of
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